SCLS413B - APRIL 1998 - REVISED SEPTEMBER 1999

- EPIC ™ (Enhanced-Performance Implanted CMOS) Process
- Typical V_{OLP} (Output Ground Bounce)
 <0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 >2 V at V_{CC} = 3.3 V, T_A = 25°C
- 8-Bit Serial-In, Parallel-Out Shift Registers With Storage
- Independent Direct Overriding Clears on Shift and Storage Registers
- Independent Clocks for Shift and Storage Registers
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 200-V Machine Model (A115-A)
 - 1000-V Charged-Device Model (C101)
- Package Options Include Plastic Small-Outline (D, NS), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

description

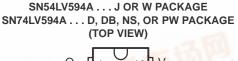
The 'LV594A devices are 8-bit shift registers designed for 2-V to 5.5-V V_{CC} operation.

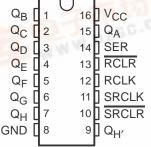
These devices contain an 8-bit serial-in, parallelout shift register that feeds an 8-bit D-type storage register. Separate clocks (RCLK, SRCLK) and

direct overriding clear (\overline{RCLR} , \overline{SRCLR}) inputs are provided on the shift and storage registers. A serial output ($Q_{H'}$) is provided for cascading purposes.

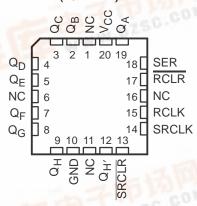
The shift-register (SRCLK) and storage-register (RCLK) clocks are positive-edge triggered. If the clocks are tied together, the shift register always is one clock pulse ahead of the storage register.

The SN54LV594A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LV594A is characterized for operation from –40°C to 85°C.





SN54LV594A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

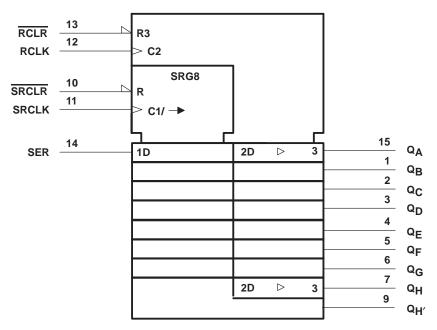




FUNCTION TABLE

		INPUTS			FUNCTION
SER	SRCLK	SRCLR	RCLK	RCLR	FUNCTION
Χ	Х	L	Х	Х	Shift register is cleared.
L	\uparrow	Н	Х	X	First stage of shift register goes low. Other stages store the data of previous stage, respectively.
Н	↑	Н	X	X	First stage of shift register goes high. Other stages store the data of previous stage, respectively.
L	\downarrow	Н	X	X	Shift register state is not changed.
X	X	X	X	L	Storage register is cleared.
Χ	X	X	\uparrow	Н	Shift register data is stored in the storage register.
X	X	X	\downarrow	Н	Storage register state is not changed.

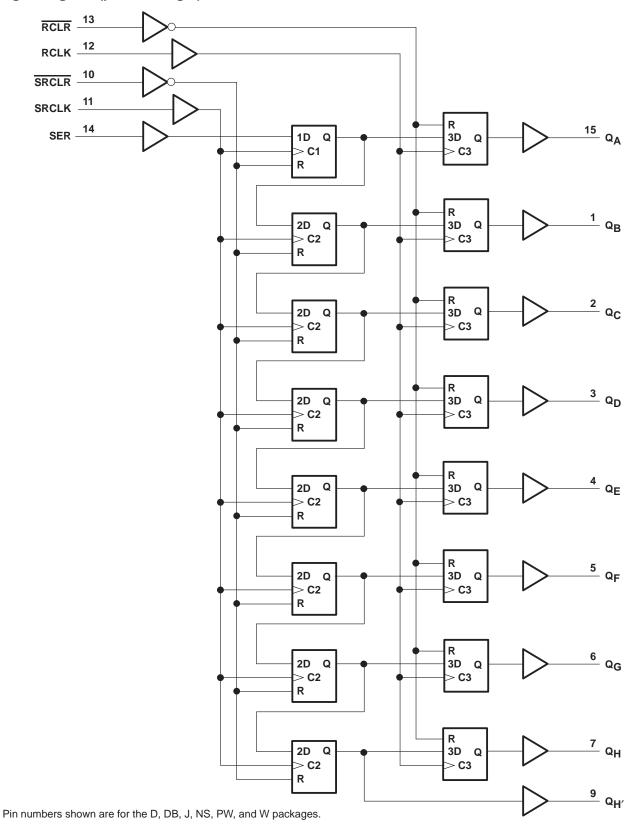
logic symbol†



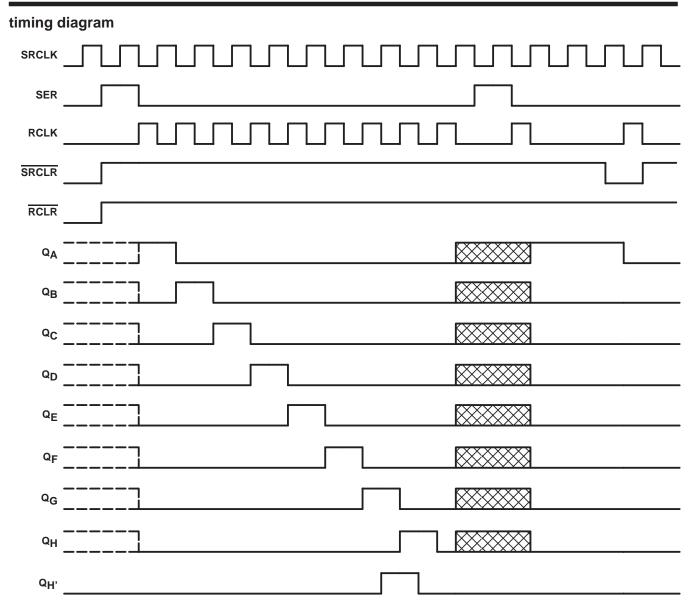
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, NS, PW, and W packages.



logic diagram (positive logic)



SN54LV594A, SN74LV594A **8-BIT SHIFT REGISTERS** WITH OUTPUT REGISTERS SCLS413B – APRIL 1998 – REVISED SEPTEMBER 1999



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (see Note 1)		–0.5 V to 7 V
Output voltage range, V _O (see Notes 1 and 2)		-0.5 V to V_{CC} + 0.5 V
Input clamp current, $I_{ K }(V_{ C } < 0)$		–20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CO}	c)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±35 mA
Continuous current through V _{CC} or GND		±70 mA
Package thermal impedance, θ _{JA} (see Note 3)): D package	73°C/W
	DB package	82°C/W
	NS package	64°C/W
	PW package	108°C/W
Storage temperature range, T _{stq}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. This value is limited to 7 V maximum.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 4)

			SN54L	V594A	SN74L	V594A	UNIT
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage		2	5.5	2	5.5	V
		V _{CC} = 2 V	1.5		1.5		
\ _{\/}	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V _{CC} ×0.7		$V_{CC} \times 0.7$		V
VIH	r ligh-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V _{CC} × 0.7		$V_{CC} \times 0.7$		v
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V _{CC} × 0.7		$V_{CC} \times 0.7$		
		$V_{CC} = 2 V$		0.5		0.5	
V _{IL}	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$,	$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	V
'	Low level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$,	$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	v
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$,	$V_{CC} \times 0.3$		$V_{CC} \times 0.3$	
٧ _I	Input voltage		0	5.5	0	5.5	V
٧o	Output voltage		0	Усс	0	Vcc	V
		V _{CC} = 2 V		– 50		-50	μΑ
	High-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	Ĉ,	– 2		-2	
ЮН	r light-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	200	-6		-6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	Q.	-12		-12	
		$V_{CC} = 2 V$		50		50	μΑ
lOL	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		2	
I IOL	Low level output current	$V_{CC} = 3 V \text{ to } 3.6 V$		6		6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12		12	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	200	0	200	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3 V \text{ to } 3.6 V$	0	100	0	100	ns/V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0	20	0	20	
TA	Operating free-air temperature		- 55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETER	TEST CONDITIONS	,,	SN54LV594A	SN74LV594A	UNIT
PARAMETER	TEST CONDITIONS	vcc	MIN TYP MAX	MIN TYP MAX	UNII
	ΙΟΗ = -50 μΑ	2 V to 5.5 V	V _{CC} -0.1	V _{CC} -0.1	
Vall	I _{OH} = -2 mA	2.3 V	2	2	V
VOH	I _{OH} = -6 mA	3 V	2.48	2.48	V
	I _{OH} = -12 mA	4.5 V	3.8	3.8	
	I _{OL} = 50 μA	2 V to 5.5 V	0.1	0.1	
\/a	I _{OL} = 2 mA	2.3 V	0.4	0.4	V
VOL	I _{OL} = 6 mA	3 V	0.44	0.44	v
	I _{OL} = 12 mA	4.5 V	0.55	0.55	
lį	$V_I = V_{CC}$ or GND	5.5 V	±1	±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	20	μΑ
l _{off}	V_I or $V_O = 0$ to 5.5 V	0 V	5	5	μΑ
C.	V _I = V _{CC} or GND	3.3 V	3.5	3.5	pF
C _i	AL = ACC OL GIAD	5 V	2	2	þΓ

timing requirements over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

			T _A =	25°C	SN54L	/594A	SN74L	/594A	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Pulse duration	RCLK or SRCLK high or low	7		7.5		7.5		no
t _W	Fuise duration	RCLR or SRCLR low	6		6.5	E	6.5		ns
		SER before SRCLK↑	2.5		3	ZEL	3		
		SRCLK↑ before RCLK↑†	8		9,4	Š.	9		
t _{su}	Setup time	SRCLR low before RCLK↑	8.5		9.5		9.5		ns
		SRCLR high (inactive) before SRCLK↑	6		6.8		6.8		
		RCLR high (inactive) before RCLK↑	6.7		7.6		7.6		
t _h	Hold time	SER after SRCLK↑	1.5		1.5		1.5		ns

[†] This setup time ensures the output register sees stable data from the shift-register outputs. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			T _A =	25°C	SN54L	V594A	SN74L	/594A	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNII
	Pulse duration	RCLK or SRCLK high or low	5.5		5.5		5.5		
t _W	Pulse duration	RCLR or SRCLR low	5		5	F	5		ns
		SER before SRCLK↑	3.5		3.5	FE	3.5		
		SRCLK↑ before RCLK↑†	8		8.5	5,	8.5		
t _{su}	Setup time	SRCLR low before RCLK↑	8		9	,	9		ns
		SRCLR high (inactive) before SRCLK↑	4.2		4.8		4.8		
		RCLR high (inactive) before RCLK↑	4.6		5.3		5.3		
th	Hold time	SER after SRCLK↑	1.5		1.5		1.5		ns

[†] This setup time ensures the output register sees stable data from the shift-register outputs. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.



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timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T _A =	25°C	SN54L	V594A	SN74L	√594A	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Pulse duration	RCLK or SRCLK high or low	5		5		5		ns
t _W	Puise duration	RCLR or SRCLR low	5.2		5.2	EV	5.2		115
		SER before SRCLK↑	3		3	EL	3		
		SRCLK↑ before RCLK↑†	5		5,4	5,	5		
t _{su}	Setup time	SRCLR low before RCLK↑	5		5		5		ns
		SRCLR high (inactive) before SRCLK↑	2.9		3.3		3.3		
		RCLR high (inactive) before RCLK↑	3.2		3.7		3.7		
t _h	Hold time	SER after SRCLK↑	2		2		2		ns

[†] This setup time ensures the output register sees stable data from the shift-register outputs. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

DADAMETED	FROM	то	LOAD	T	λ = 25°C	;	SN54L	/594A	SN74L\	/594A	LINUT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF*	65	80		45		45		MHz
fmax			C _L = 50 pF	60	70		40		40		IVITZ
^t PLH*	BOLK	0 - 0 -			6.4	10.6	1	11.1	1	11.1	
^t PHL*	RCLK	Q _A –Q _H]		6.3	10.4	1	11.1	1	11.1	
^t PLH*	CDCI K	0	0. 15 75		7.4	12.1	1	12.8	1	12.8	
^t PHL*	SRCLK	Q _H ′	C _L = 15 pF		7.2	11.6	1	12.8	1	12.8	ns
^t PHL*	RCLR	Q _A –Q _H]		7.9	12.7	1,	13.6	1	13.6	
^t PHL*	SRCLR	Q _H ′			7.4	11.9	³ 7/ ₂	13.1	1	13.1	
^t PLH	BOLK	0 0			9.5	14.1	0/1	14.6	1	14.6	
^t PHL	RCLK	Q _A –Q _H			10.8	15.5	Q 1	17.2	1	17.2	
^t PLH	SDCI K	0	C 50 pF		10.6	15.7	1	16.5	1	16.5	no
^t PHL	SRCLK	Q _H ′	C _L = 50 pF		11.3	16.1	1	18.6	1	18.6	ns
^t PHL	RCLR	Q _A –Q _H]		12.1	17.4	1	19	1	19	
^t PHL	SRCLR	$Q_{H'}$]		11.6	16.5	1	18.6	1	18.6	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.



SN54LV594A, SN74LV594A 8-BIT SHIFT REGISTERS WITH OUTPUT REGISTERS

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	չ = 25°C	;	SN54L	/594A	SN74L	/594A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF*	80	120		70		70		MHz
fmax			C _L = 50 pF	55	105		50		50		IVII IZ
tPLH*	DOLK.	00			4.6	8	1	8.5	1	8.5	
tPHL*	RCLK	Q _A –Q _H			4.9	8.2	1	8.8	1	8.8	
tPLH*	000114		0. 45.5		5.4	9.1	1	9.7	1	9.7	
t _{PHL} *	SRCLK	Q _H ′	C _L = 15 pF		5.5	9.2	1	49.9	1	9.9	ns
^t PHL*	RCLR	Q _A –Q _H			6	9.8	1,	10.6	1	10.6	
tPHL*	SRCLR	Q _H ′			5.6	9.2	37/	10	1	10	
t _{PLH}	BOLK	00			6.9	10.5	01	11.1	1	11.1	
t _{PHL}	RCLK	Q _A –Q _H] [8.1	11.9	Q 1	13.1	1	13.1	
t _{PLH}	CDCI IX	0	C. 50 pF		7.7	11.7	1	12.4	1	12.4	
t _{PHL}	SRCLK	Q _H ′	$C_L = 50 pF$		8.4	12.5	1	13.9	1	13.9	ns
^t PHL	RCLR	Q _A –Q _H] [9.1	13.1	1	14.4	1	14.4	
t _{PHL}	SRCLR	$Q_{H'}$			8.5	12.4	1	14	1	14	

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	ղ = 25°C	;	SN54L\	/594A	SN74L\	/594A	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF*	135	170		115		115		MHz
fmax			C _L = 50 pF	120	140		95		95		IVITZ
tPLH*	DOLK	0 . 0			3.3	6.2	1	6.5	1	6.5	
tPHL*	RCLK	Q_A-Q_H			3.7	6.5	1	6.9	1	6.9	
tPLH*	000114		0. 455		3.7	6.8	1	7.2	1	7.2	
tPHL*	SRCLK	QH′	C _L = 15 pF		4.1	7.2	1	7.6	1	7.6	ns
tPHL*	RCLR	Q _A –Q _H			4.5	7.6	1,	8.2	1	8.2	
tPHL*	SRCLR	Q _H ′			4.1	7.1	37/	7.6	1	7.6	
t _{PLH}	DOLK	0 0			4.9	7.8	0	8.3	1	8.3	
t _{PHL}	RCLK	Q_A-Q_H			5.8	8.9	Q 1	9.7	1	9.7	
^t PLH	000114		0 50 55		5.5	8.6	1	9.1	1	9.1	
^t PHL	SRCLK	Q _H ′	$C_L = 50 pF$		6	9.2	1	10.1	1	10.1	ns
^t PHL	RCLR	Q _A –Q _H			6.6	10	1	10.7	1	10.7	
t _{PHL}	SRCLR	$Q_{H'}$			6	9.2	1	10.1	1	10.1	

 $^{^{\}star}$ On products compliant to MIL-PRF-38535, this parameter is not production tested.



SN54LV594A, SN74LV594A 8-BIT SHIFT REGISTERS WITH OUTPUT REGISTERS SCLS413B – APRIL 1998 – REVISED SEPTEMBER 1999

noise characteristics, V_{CC} = 3.3 V, C_L = 50 pF, T_A = 25°C (see Note 5)

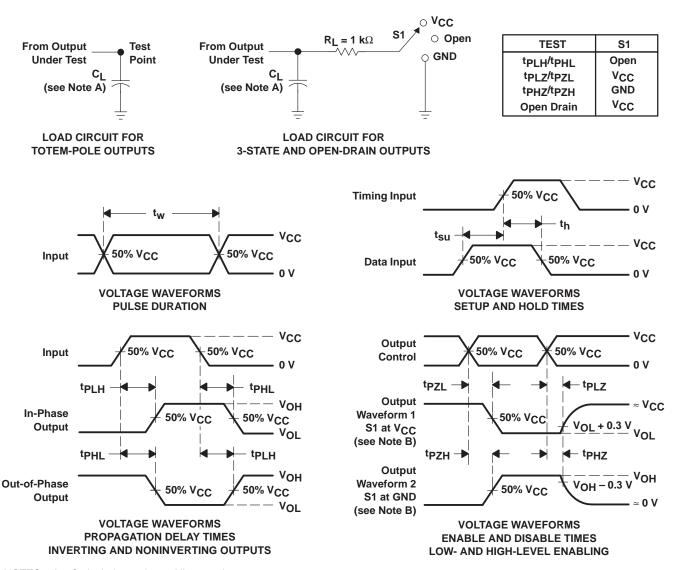
	PARAMETER	SN	74LV594	A	UNIT
	PARAMETER	MIN	TYP	MAX	UNII
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.5	0.8	V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.1	-0.8	V
V _{OH(V)}	Quiet output, minimum dynamic VOH		2.8		V
VIH(D)	High-level dynamic input voltage	2.31			V
V _{IL(D)}	Low-level dynamic input voltage			0.99	V

NOTE 5: Characteristics are for surface-mount packages only.

operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	VCC	TYP	UNIT
Card	Power dissipation capacitance	f = 10 MHz	3.3 V	93	pF
Cpd	i ower dissipation capacitance	1 = 10 WII 12	5 V	112	ρι

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
- $\label{eq:defD} \textbf{D.} \quad \text{The outputs are measured one at a time with one input transition per measurement.}$
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpHL and tpLH are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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